Notice of References Cit d

Application/Control No.

10/002,978

Examiner

Thao X Le

Applicant(s)/Patent Under
Reexamination
HSIEH ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,163,050	12-2000	Hisatomi et al.	257/324
	В	US-6,187,633	02-2001	Dong et al.	438/261
	С	US-4,954,867	09-1990	Hosaka, Takashi	257/639
	D	US-6,235,652	05-2001	Cook et al.	438/787
	E	US-5,814,551	09-1998	Park et al.	438/448
	F	US-6,504,233 .	01-2003	Gorczyca et al.	257/629
	G	US-6,368,919	04-2002	Nuttall et al.	438/261
	Н	US-5,930,658	07-1999	Ibok, Effiong E.	438/482
	ı	US-5,981,404	11-1999	Sheng et al.	438/791
	J	US-6,177,311	01-2001	Kauffman et al.	438/257
	К	US-6,395,644	05-2002	Hopper et al.	438/738
	L	US-5,869,394	02-1999	Chen et al.	438/624
	М	US-2002/0068398	06-2002	Dong et al.	438/201

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.